

What is claimed is:

1. An analog/digital characteristics testing device comprising:

a plurality of measurement circuits for measuring an analog/digital characteristic of one or more ICs to be tested in accordance with a test condition data; and

a setting unit for setting a different test condition data to each measurement circuit.

2. The analog/digital characteristics testing device as claimed in claim 1, wherein the setting unit comprises:

a test condition outputting circuit for outputting the test condition data in order;

a counting circuit for counting the number of the test condition data outputted from the test condition outputting circuit; and

a specifying circuit for specifying the measurement circuit in which the test condition data is written, in accordance with a counter value of the counting circuit.

3. The analog/digital characteristics testing device as claimed in claim 2, wherein when an initial test condition data is outputted from the test condition outputting circuit, the specifying circuit specifies all of the measurement circuits as a circuit in which the initial test condition data is written.

4. The analog/digital characteristics testing device as claimed in claim 1, further comprising a management unit for managing a test result data obtained by each measurement circuit.

5. The analog/digital characteristics testing device as claimed in claim 4, wherein the setting unit comprises:

a test condition outputting circuit for outputting the test condition data in order; and

a counting circuit for counting the number of the test condition data outputted from the test condition outputting circuit; and

the management unit comprises:

a multiplexing circuit for outputting the test result data obtained by each measurement circuit, from a predetermined output terminal in accordance with a counter value of the counting circuit; and

a judging circuit for judging whether the one or more ICs to be tested are good or poor in accordance with the test result data outputted from the multiplexing circuit.

6. An analog/digital characteristics testing device comprising:

a test condition outputting circuit for outputting one or more test condition data;

a plurality of measurement circuits for measuring an analog/digital characteristic of one or more ICs to be tested

in accordance with the test condition data; and

a setting unit for setting the test condition data to each measurement circuit;

wherein when the test condition outputting circuit outputs one test condition data, the setting unit sets the outputted one test condition data to all of the measurement circuits; and when the test condition outputting circuit outputs a plurality of test condition data, the setting unit selects one test condition data to be set to each measurement circuit, from the plurality of test condition data.

7. The analog/digital characteristics testing device as claimed in claim 6, wherein the setting unit comprises a counting circuit for counting the number of the test condition data outputted from the test condition outputting circuit;

wherein the setting unit sets the test condition data to each measurement circuit in accordance with the number of test condition data, which is counted by the counting circuit.

8. The analog/digital characteristics testing device as claimed in claim 6, further comprising a multiplexing circuit for multiplexing a plurality of test result data obtained by measuring the analog/digital characteristic of the one or more ICs to be tested with the plurality of measurement circuits.

9. An IC testing apparatus comprising:

an analog/digital characteristics testing device comprising: a plurality of measurement circuits for measuring an analog/digital characteristic of one or more ICs to be tested in accordance with a test condition data; and a setting unit for setting a different test condition data to each measurement circuit.

10. The IC testing apparatus as claimed in claim 9, wherein the setting unit comprises:

a test condition outputting circuit for outputting the test condition data in order;

a counting circuit for counting the number of the test condition data outputted from the test condition outputting circuit; and

a specifying circuit for specifying the measurement circuit in which the test condition data is written, in accordance with a counter value of the counting circuit.

11. The IC testing apparatus as claimed in claim 10, wherein when an initial test condition data is outputted from the test condition outputting circuit, the specifying circuit specifies all of the measurement circuits as a circuit in which the initial test condition data is written.

12. The IC testing apparatus as claimed in claim 9, wherein the analog/digital characteristics testing device

further comprises a management unit for managing a test result data obtained by each measurement circuit.

13. The IC testing apparatus as claimed in claim 12, wherein the setting unit comprises:

a test condition outputting circuit for outputting the test condition data in order; and

a counting circuit for counting the number of the test condition data outputted from the test condition outputting circuit; and

the management unit comprises:

a multiplexing circuit for outputting the test result data obtained by each measurement circuit, from a predetermined output terminal in accordance with a counter value of the counting circuit; and

a judging circuit for judging whether the one or more ICs to be tested are good or poor in accordance with the test result data outputted from the multiplexing circuit.

14. An IC testing apparatus comprising:

an analog/digital characteristics testing device comprising: a test condition outputting circuit for outputting one or more test condition data; a plurality of measurement circuits for measuring an analog/digital characteristic of one or more ICs to be tested in accordance with the test condition data; and a setting unit for setting the test condition data

to each measurement circuit;

wherein when the test condition outputting circuit outputs one test condition data, the setting unit sets the outputted one test condition data to all of the measurement circuits; and when the test condition outputting circuit outputs a plurality of test condition data, the setting unit selects one test condition data to be set to each measurement circuit, from the plurality of test condition data.

15. The IC testing apparatus as claimed in claim 14, wherein the setting unit comprises a counting circuit for counting the number of the test condition data outputted from the test condition outputting circuit;

wherein the setting unit sets the test condition data to each measurement circuit in accordance with the number of test condition data, which is counted by the counting circuit.

16. The IC testing apparatus as claimed in claim 14, wherein the analog/digital characteristics testing device further comprises a multiplexing circuit for multiplexing a plurality of test result data obtained by measuring the analog/digital characteristic of the one or more ICs to be tested with the plurality of measurement circuits.